

Features

- Frequency: 32-38GHz
- Small Signal Gain: 28dB
- Psat: 28.5dBm
- PAE: 18%
- Power Supply: +5V@730mA
- Input/Output: 50Ω
- Die Size: 2.77 x 1.59 x 0.1mm

Typical Applications

- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics


Electrical Specifications

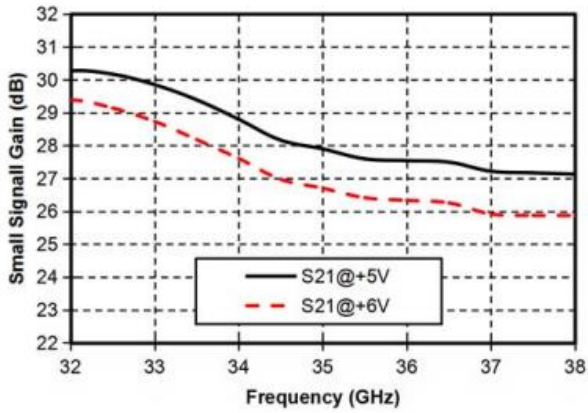
TA = +25°C, Vd = +5V, Ids = 730mA

Parameters	Min.	Typ.	Max.	Units
Frequency	32-38			GHz
Small Signal Gain	-	28	-	dB
Gain Flatness	±1.5			dB
Psat	-	28.5	-	dBm
PAE	18			%
Input Return Loss	-	8	-	dB
Output Return Loss	-	12	-	dB

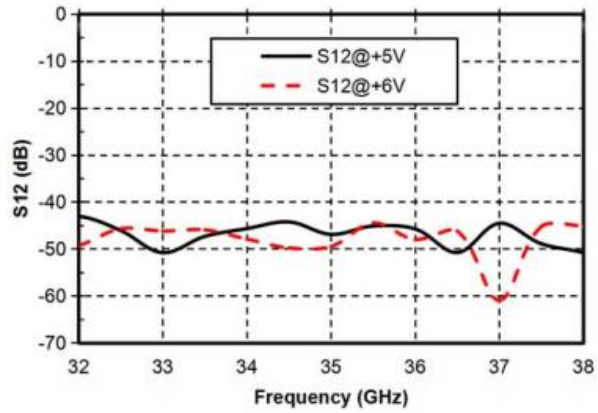
* By tuning the Vg terminal voltage -2V~0V, the Vg terminal voltage is recommended to be -0.6V.



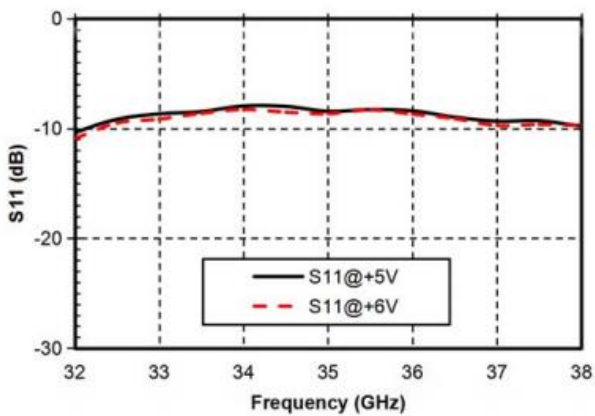
Gain vs. Frequency



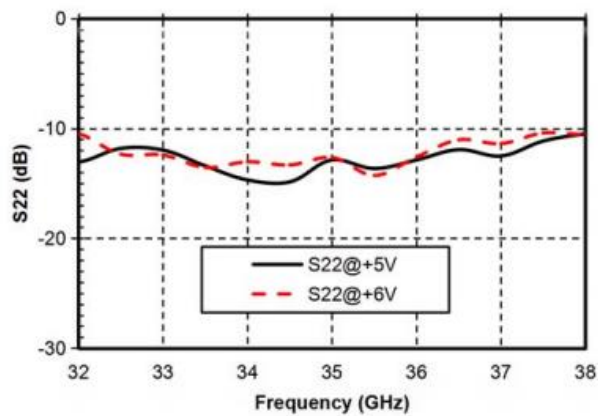
Reverse Isolation vs. Frequency



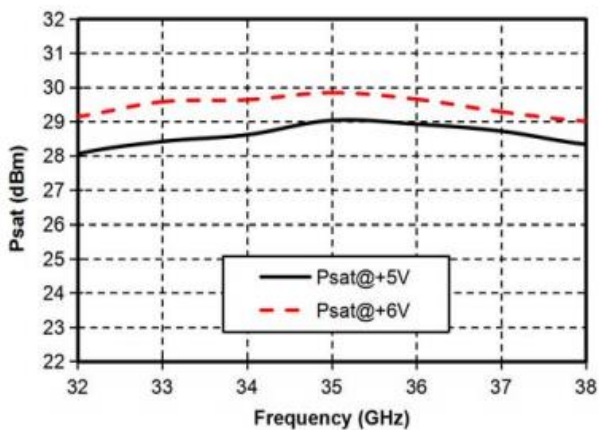
Input Return Loss vs. Frequency



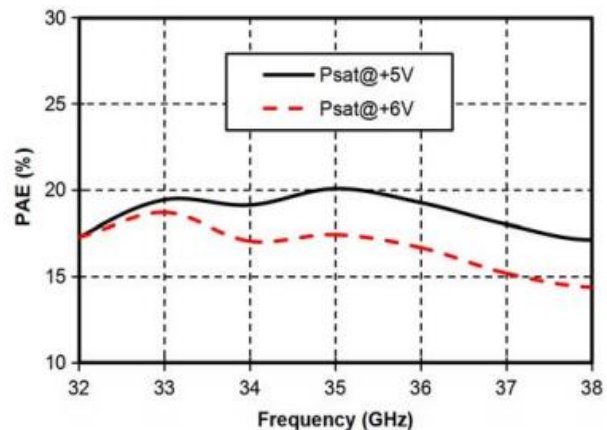
Output Return Loss vs. Frequency



Psat vs. Frequency

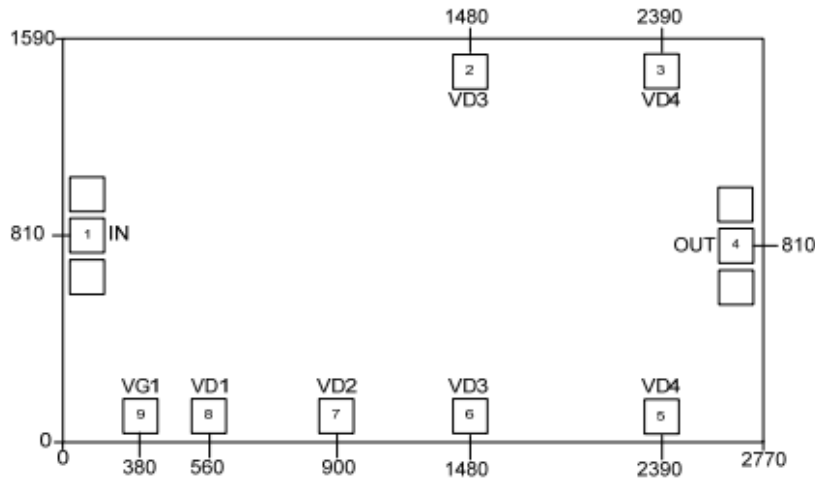


PAE vs. Frequency





Outline Drawing:
All Dimensions in um

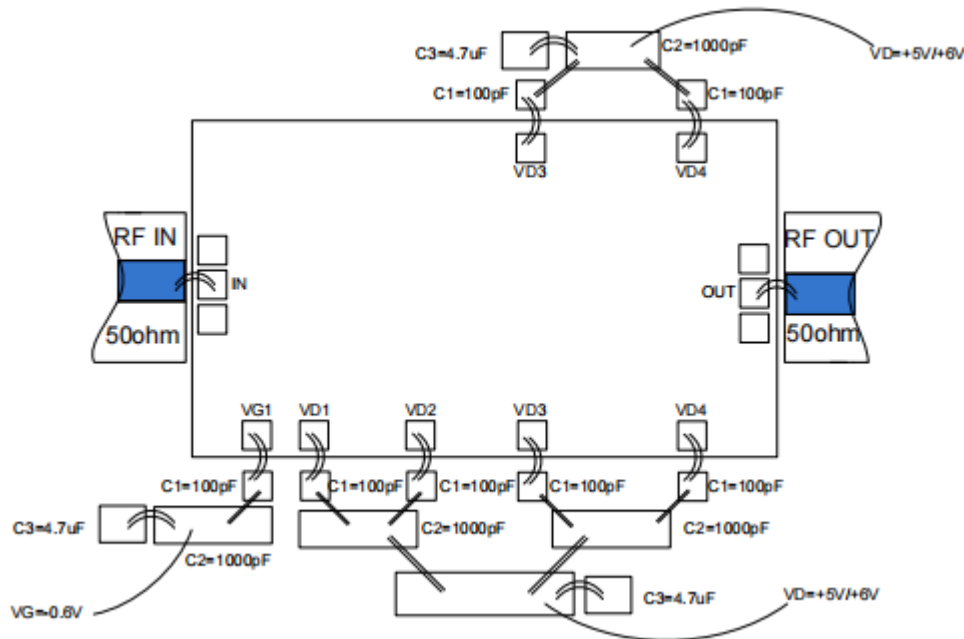


Pad Description

PAD	Function	Description
1	RF IN	RF signal input terminal, no blocking capacitor required
4	RF OUT	RF signal output terminal, no blocking capacitor required
2,3,5,6,7,8	VD1,VD2,VD3, VD4	Amplifier drain bias, connected to external 100pF ,1000pF, 4.7uF bypass capacitor.
9	VG	Amplifier gate bias, connected to external 100pF ,1000pF, 4.7uF bypass capacitor.
Die Bottom	GND	Die bottom must be connected to RF/DC ground



Assembly Drawing



Notes:

1. Die thickness: 100um
2. Typical bond pad is 100*100 μm^2
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

Maximum Ratings:

1. Maximum drain voltage: +8V
2. Maximum input power: +20dBm
3. Operating temperature: -55°C to +85°C
4. Storage temperature: -65°C to +150°C